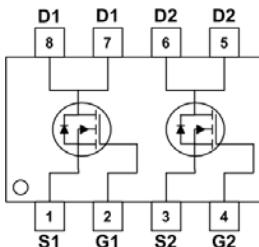
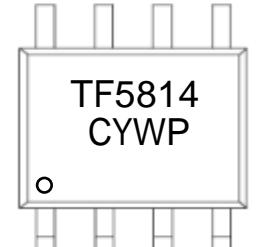


SOP-8 Plastic-Encapsulate MOSFETS

TF5814

N-Channel Enhancement Mode Power MOSFET

General Description		Product Summary		
<p>The TF5814 is the highest performance trench N-ch MOSFET with extreme high cell density, which provide excellent RDSON and gate chargens for most of the synchronous buck converter applications .</p> <p>The TF5814 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.</p>		BVDSS	RDSON	ID
		57V	17 mΩ	9A
SOP-8				Schematic diagram
			Y :year code W :week code	

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	57	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	9.0	A
$I_D @ T_C = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	7.0	A
I_{DM}	Pulsed Drain Current ²	35	A
EAS	Single Pulse Avalanche Energy ³	23	mJ
I_{AS}	Avalanche Current	9	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation ⁴	2.0	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹	---	40	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	---	62.5	°C/W



SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

SOP-8 Plastic-Encapsulate MOSFETs**TF5814****Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	57	---	---	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=8\text{A}$	---	17	20	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_D=7\text{A}$	---	20	28	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$	1.1	1.5	2.1	V
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=55\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_D=8\text{A}$	---	30	---	S
R_g	Gate Resistance	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	2.1	---	Ω
Q_g	Total Gate Charge (4.5V)	$V_{\text{DS}}=25\text{V}$, $V_{\text{GS}}=10\text{V}$, $I_D=8\text{A}$	---	23	---	nC
Q_{gs}	Gate-Source Charge		---	4.6	---	
Q_{gd}	Gate-Drain Charge		---	12	---	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=25\text{V}$, $V_{\text{GEN}}=10\text{V}$, $R_G=6.7\Omega$ $R_L=3\Omega$	---	9.6	---	ns
T_r	Rise Time		---	4.7	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	25.2	---	
T_f	Fall Time		---	4.7	---	
C_{iss}	Input Capacitance	$V_{\text{DS}}=25\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	1000	---	pF
C_{oss}	Output Capacitance		---	108	---	
C_{rss}	Reverse Transfer Capacitance		---	96	---	

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	$V_{\text{DD}}=25\text{V}$, $L=0.5\text{mH}$, $I_{\text{AS}}=8\text{A}$	23	---	---	mJ

Diode Characteristics

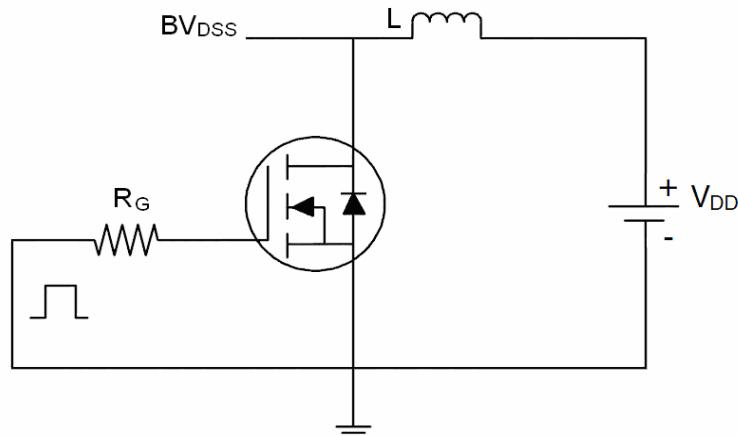
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,6}	$V_G=V_D=0\text{V}$, Force Current	---	---	2	A
I_{SM}	Pulsed Source Current ^{2,6}		---	---	35	A
V_{SD}	Diode Forward Voltage ²	$V_{\text{GS}}=0\text{V}$, $I_s=2.3\text{A}$, $T_J=25^\circ\text{C}$	---	0.8	1.1	V
t_{rr}	Reverse Recovery Time	$I_F=8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$	---	6	---	nS
Q_{rr}	Reverse Recovery Charge	---	---	3.9	---	nC

Note :

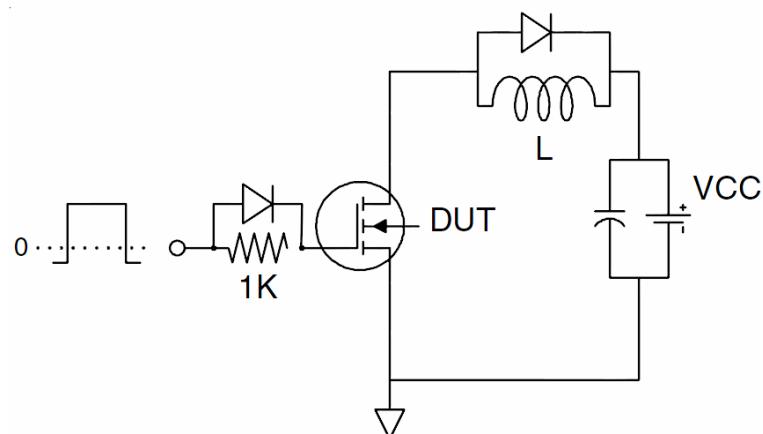
- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=25\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.5\text{mH}$, $I_{\text{AS}}=9\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The Min. value is 100% EAS tested guarantee.
- 6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Test Circuit

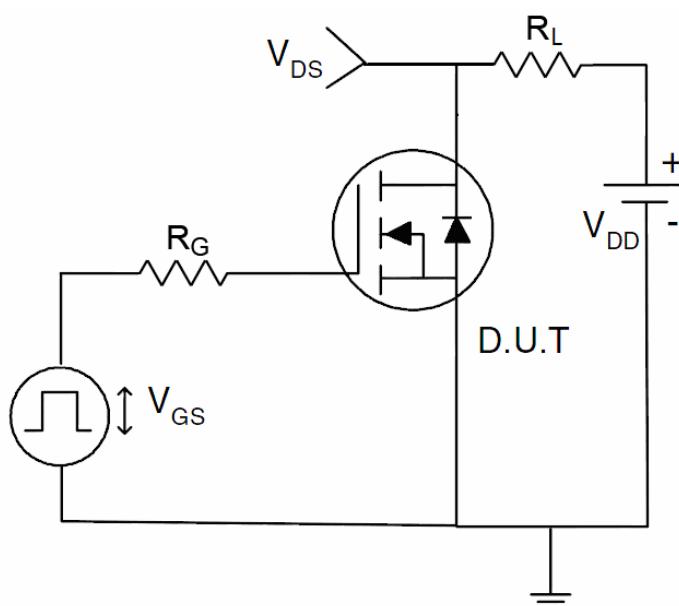
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

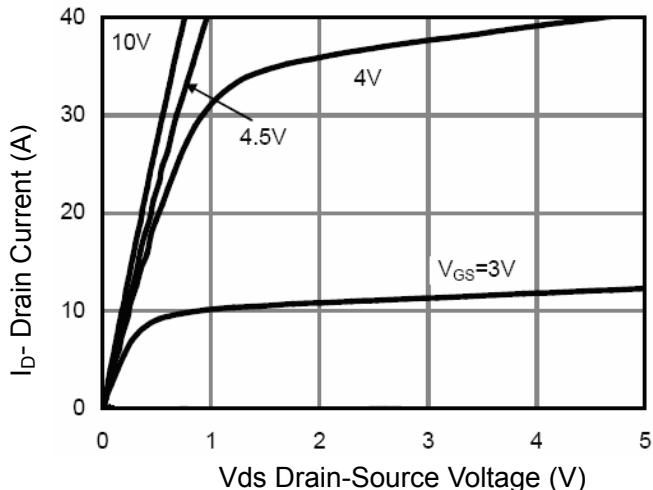


Figure 1 Output Characteristics

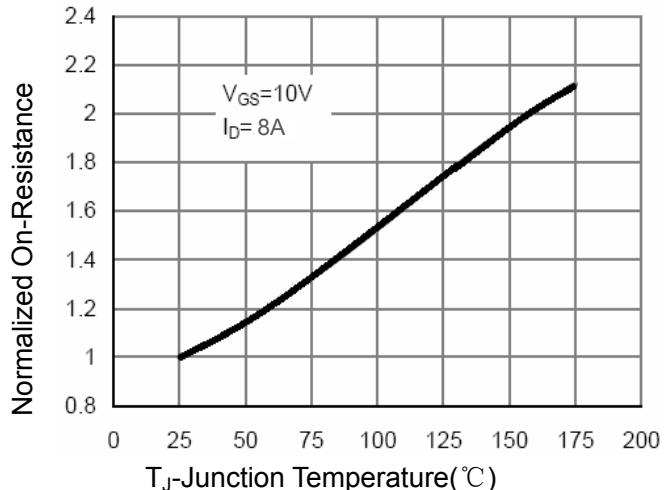


Figure 4 Rdson-Junction Temperature

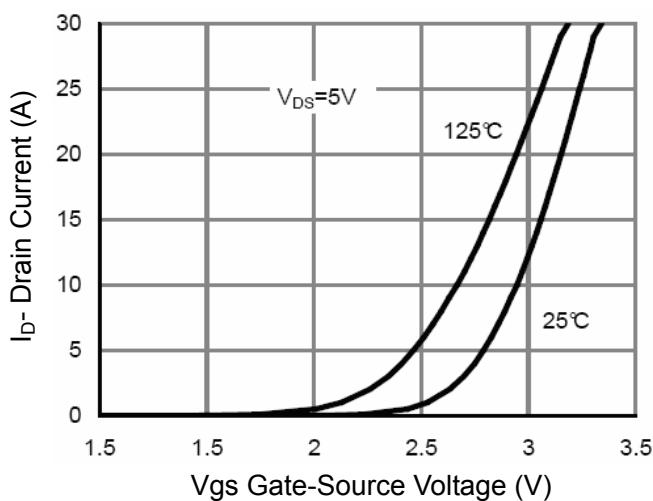


Figure 2 Transfer Characteristics

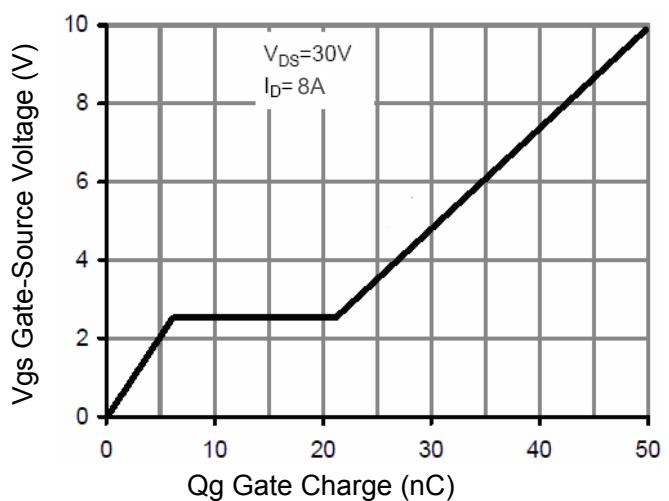


Figure 5 Gate Charge

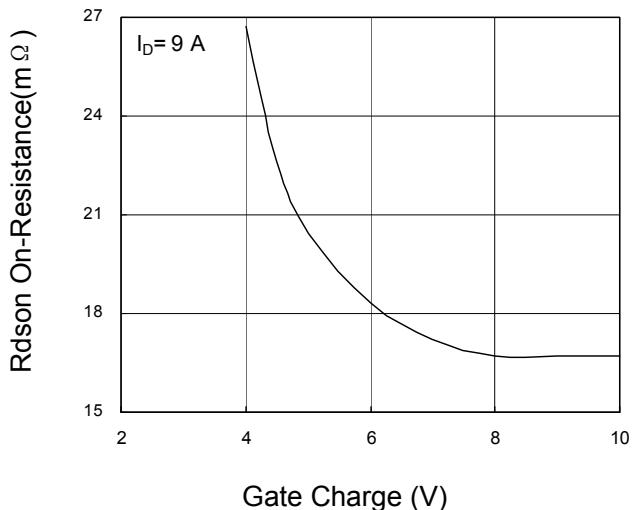


Figure 3 Rdson-Gate Charge

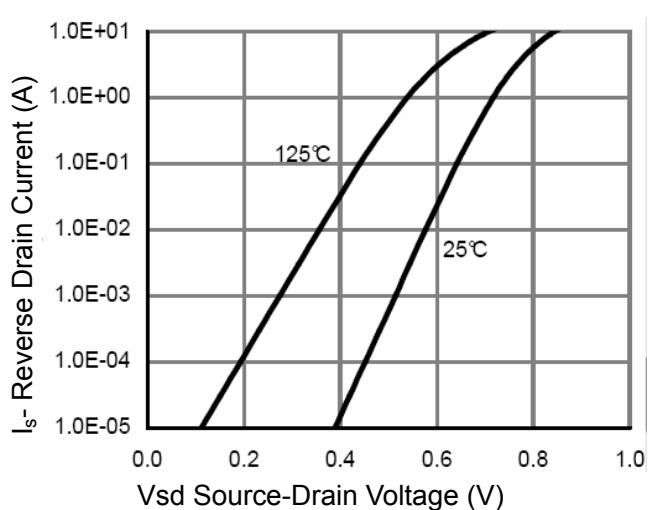


Figure 6 Source-Drain Diode Forward

SOP-8 Plastic-Encapsulate MOSFETs

TF5814

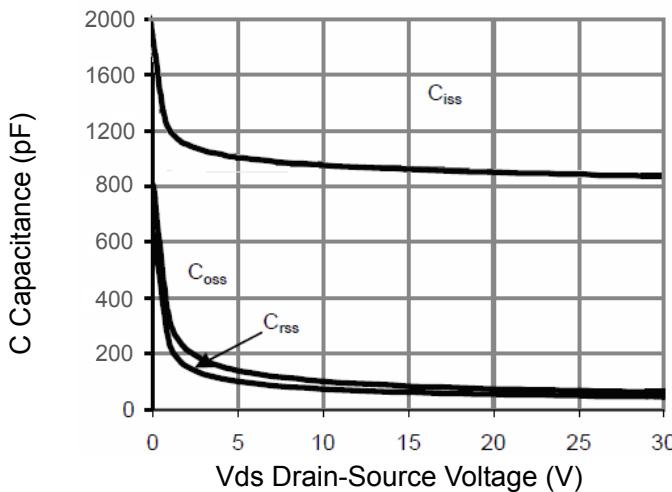


Figure 7 Capacitance vs V_{ds}

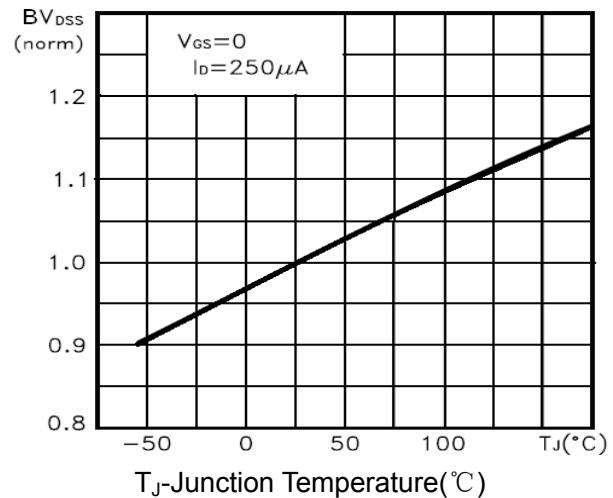


Figure 9 BV_{DSS} vs Junction Temperature

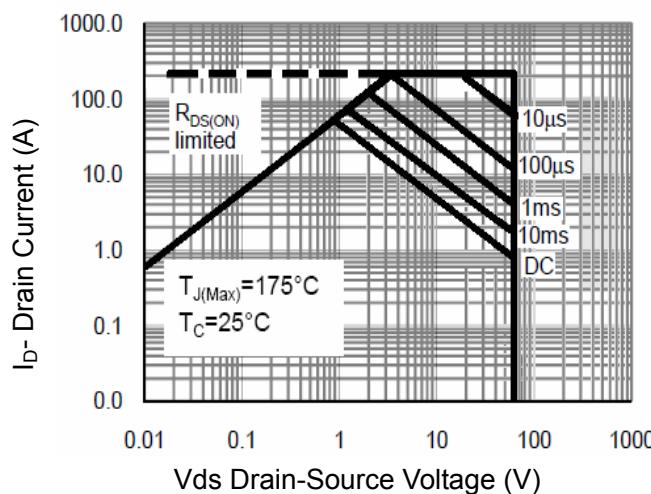


Figure 8 Safe Operation Area

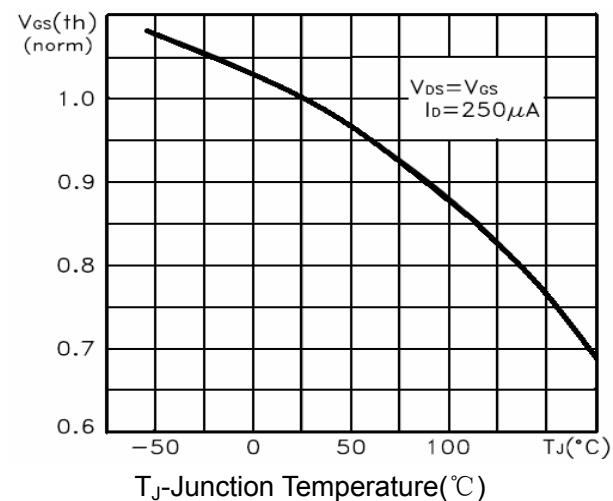


Figure 10 $V_{GS(th)}$ vs Junction Temperature

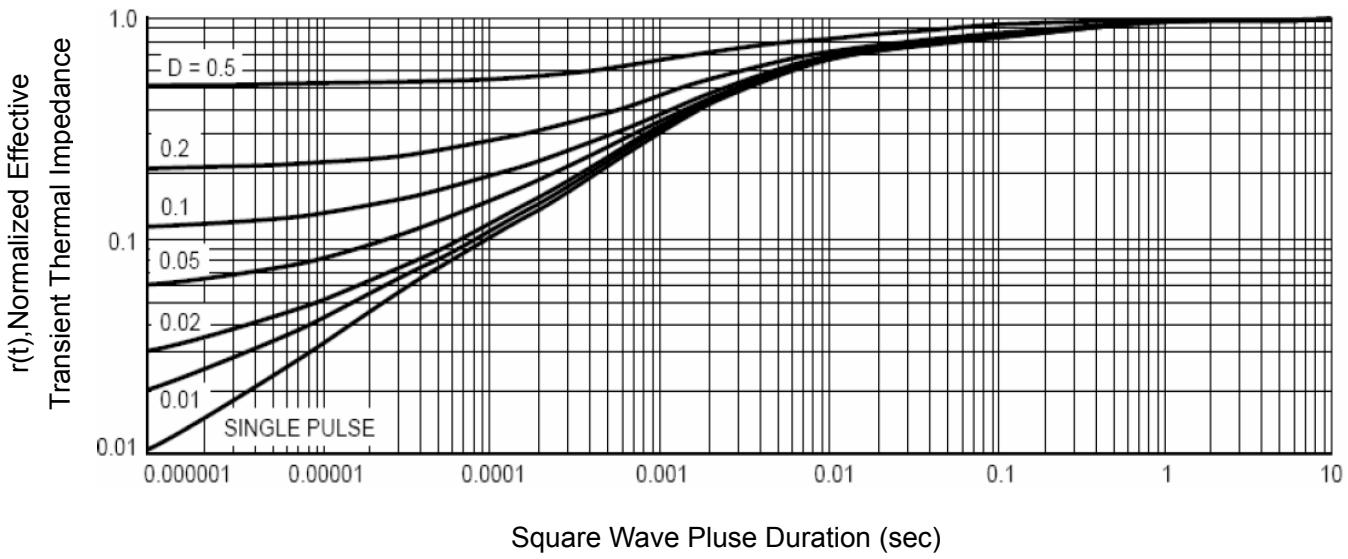
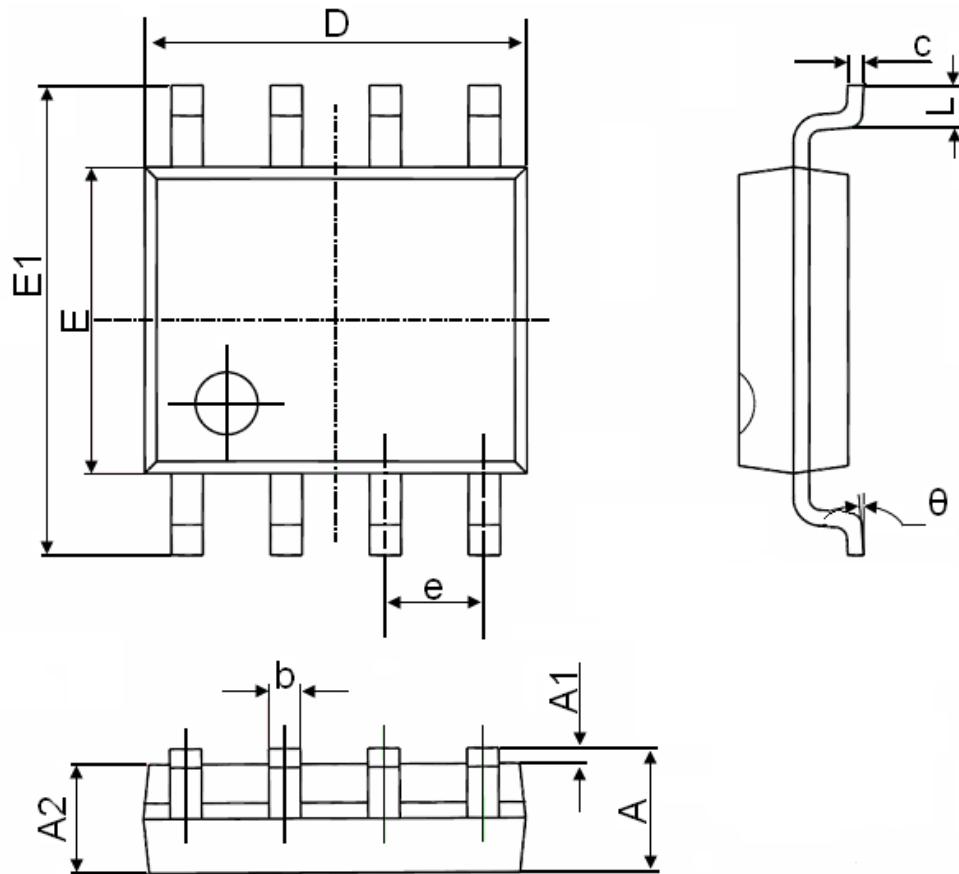


Figure 11 Normalized Maximum Transient Thermal Impedance

SOP-8 Package Information


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°